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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/772,952	02/04/2004	Yoshiro Udagawa	1232-5277	5312
27123 7590 10/09/2007 MORGAN & FINNEGAN, L.L.P.			EXAMINER	
3 WORLD FIN	ANCIAL CENTER	•	QUIETT, CARRAMAH J	
NEW YORK, N	NY 10281-2101		ART UNIT PAPER NUMBER	
			2622	
			NOTIFICATION DATE	DELIVERY MODE
			10/09/2007	ELECTRONIC

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

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•	Application No.	Applicant(s)		
	10/772,952	UDAGAWA, YOSHIRO		
Office Action Summary	Examiner	Art Unit		
•	Carramah J. Quiett	2622		
The MAILING DATE of this communication ap	ppears on the cover sheet w	ith the correspondence address		
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING IDENTIFY OF THE MAILING I	DATE OF THIS COMMUNI. 136(a). In no event, however, may a side will apply and will expire SIX (6) MON te, cause the application to become Al	CATION. reply be timely filed NTHS from the mailing date of this communication. BANDONED (35 U.S.C. § 133).		
Status	•			
 Responsive to communication(s) filed on <u>02</u>. This action is FINAL. Since this application is in condition for allow closed in accordance with the practice under 	is action is non-final. ance except for formal mat	•		
Disposition of Claims				
4) ☐ Claim(s) 1-8 is/are pending in the application. 4a) Of the above claim(s) is/are withdra 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-8 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/	awn from consideration.			
Application Papers				
9) The specification is objected to by the Examin 10) The drawing(s) filed on 04 February 2004 is/a Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examination.	re: a)⊠ accepted or b)☐ e drawing(s) be held in abeyar ction is required if the drawing	nce. See 37 CFR 1.85(a). (s) is objected to. See 37 CFR 1.121(d).		
Priority under 35 U.S.C. § 119	,			
12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) △ All b) ☐ Some * c) ☐ None of: 1. △ Certified copies of the priority documents have been received. 2. ☐ Certified copies of the priority documents have been received in Application No 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received.				
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date	Paper No(Summary (PTO-413) s)/Mail Date nformal Patent Application		

DETAILED ACTION

Response to Amendment

1. The amendment(s), filed on 07/02/2007, have been entered and made of record. Claims 1-8 are pending.

Response to Arguments

2. Applicant's arguments filed 07/02/2007 have been fully considered but they are not persuasive.

The Applicant asserts that the cited prior art, Kidono et al. – U.S. Pat. #6,970,193 (herein referred to as Kidono) does not teach "the correction means" as recited in claim 1. On pages 5 and 6 of the Remarks (filed 07/02/2007), the Applicant states that (in reference to the Kidono reference), "...the eliminating of smears of image signals is based upon the correction reference signal which is generated in the digital process circuit, not based upon a reference signal stored in the EEPROM, which the office action asserts discloses the "pixel defect information storage means"..." The Examiner respectfully disagrees. In col. 8, lines 31-36, Kidono additionally explains that, "The image signal of the effective pixel region EP after the smear correction processing is furthermore subjected to pixel defect compensation by a known pixel defect compensation means. Such processing is rendered at the digital process circuit 8 on the basis of fault pixel address data stored in the EEPROM 8."

Accordingly, Kidono satisfies the claimed limitations of Applicant's claim 1. Therefore, the Examiner maintains the prior art rejections to claims 1-8 of the present application.

Application/Control Number: 10/772,952 Page 3

Art Unit: 2622

Claim Rejections - 35 USC § 101

3. 35 U.S.C. 101 reads as follows:

Whoever invents or discovers any new and useful process, machine, manufacture, or composition of matter, or any new and useful improvement thereof, may obtain a patent therefor, subject to the conditions and requirements of this title.

4. Claim 8 is rejected under 35 U.S.C. 101 because the claimed invention is directed to non-statutory subject matter. It is improper to not have a computer for executing a program for an image sensing apparatus as recited in claim 8. When a claim is directed to a computer program, the preamble should be written as (for example), "A computer-readable recording medium encoded with a computer program..."

Claim Rejections - 35 USC § 102

- 5. The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.
- 6. Claims 1-8 are rejected under 35 U.S.C. 102(e) as being anticipated by Kidono et al. (U.S. Pat. #6,970,193).

For **claim 1**, Kidono discloses an image sensing apparatus (fig. 1) having an image sensing device (5) (col. 3, lines 59 – col. 4, line 31), comprising:

driving means (6) for driving the image sensing device by a plurality of driving schemes (col. 4, lines 7-31);

pixel defect information storage means (18) for storing pixel defect information as information about a pixel defect in the image sensing device in correspondence with each driving scheme (col. 5, lines 25-37); and

Application/Control Number: 10/772,952

Art Unit: 2622

correction means (8) for correcting the pixel defect by referring to the pixel defect information in said pixel defect information storage means in accordance with the driving scheme with which said driving means drives the image sensing device (col. 4, lines 18-31).

For claim 2, Kidono discloses the image sensing apparatus wherein the pixel defect information is formed from basic pixel defect information generated by driving the image sensing device by a basic driving scheme and detecting the pixel defect and the other pixel defect information corresponding to the other driving scheme, which is generated on the basis of a relationship between said other driving scheme and the basic driving scheme and the basic pixel defect information (col. 4, line 60 – col. 5, line 63).

For **claim 3**, Kidono discloses the image sensing apparatus wherein the basic driving scheme is a driving scheme that reads all pixels of the image sensing device (the effective region and the OB region; col. 4, line 60 – col. 5, line 63).

For **claim 4**, Kidono discloses the image sensing apparatus wherein a data amount of said other pixel defect information is smaller than that of the basic pixel defect information (OB region; col. 4, line 60 – col. 5, line 63).

For claim 5, Kidono discloses the image sensing apparatus wherein said pixel defect information storage means is a nonvolatile recording medium (EEPROM; col. 5, lines 25-37).

For **claim 6**, Kidono teaches an image sensing method using an image sensing apparatus having an image sensing device (col. 3, lines 59 – col. 4, line 31) and driving means for driving the image sensing device by a plurality of driving schemes (col. 4, lines 7-31), comprising:

correcting a pixel defect by referring to pixel defect information in pixel defect information storage means in accordance with the driving scheme with which the driving means

Art Unit: 2622

drives the image sensing device (col. 4, lines 18-31), the pixel defect information storage means storing the pixel defect information as information about the pixel defect in the image sensing device in correspondence with each driving scheme (col. 5, lines 25-37).

For **claim 7**, Kidono discloses a computer-readable recording medium which records a program for an image sensing apparatus (inherent because the system controller controls the camera; col. 3, lines 59 – col. 4, line 31) having an image sensing device (5) and driving means (6) for driving the image sensing device by a plurality of driving schemes (col. 4, lines 7-31), characterized by causing a computer (12) in the image sensing apparatus to execute processing for correcting a pixel defect by referring to pixel defect information in pixel defect information storage means in accordance with the driving scheme with which the driving means drives the image sensing device (col. 4, lines 7-31), the pixel defect information storage means (18) storing the pixel defect information as information about the pixel defect in the image sensing device in correspondence with each driving scheme (col. 5, lines 25-37).

For **claim 8**, Kidono discloses a program for an image sensing apparatus (inherent because the system controller controls the camera; col. 3, lines 59 – col. 4, line 31) having an image sensing device (5) and driving means (6) for driving the image sensing device by a plurality of driving schemes (col. 4, lines 7-31), characterized by causing a computer (12) in the image sensing apparatus to execute processing for correcting a pixel defect by referring to pixel defect information in pixel defect information storage means in accordance with the driving scheme with which the driving means drives the image sensing device (col. 4, lines 7-31), the pixel defect information storage means (18) storing the pixel defect information as information

Application/Control Number: 10/772,952

Art Unit: 2622

about the pixel defect in the image sensing device in correspondence with each driving scheme (col. 5, lines 25-37).

Conclusion

7. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Carramah J. Quiett whose telephone number is (571) 272-7316. The examiner can normally be reached on 8:00-5:00 M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, NgocYen Vu can be reached on (571) 272-7320. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/772,952

Art Unit: 2622

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

CJQ

September 28, 2007

SUPERVISORY PATENT EXAMINER

Page 7